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Contact us

Tel: +86-755-8981 8866 Fax: +86-755-8427 6832

Email & Skype: info@chipsmall.com Web: www.chipsmall.com

Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China









STP8NK80Z - STP8NK80ZFP STW8NK80Z

N-channel 800V - 1.3Ω - 6.2A - TO-220 /TO-220FP/TO-247 Zener-protected SuperMESH™ Power MOSFET

Features

Туре	V _{DSS}	R _{DS(on)}	I _D
STP8NK80Z	800 V	< 1.5 Ω	6.2 A
STP8NK80ZFP	800 V	< 1.5 Ω	6.2 A
STW8NK80Z	800 V	< 1.5 Ω	6.2 A

- Extremely high dv/dt capability
- 100% avalanche tested
- Gate charge minimized
- Very low intrinsic capacitances
- Very good manufacturing repeatability



The SuperMESH™ series is obtained through an extreme optimization of ST's well established strip-based PowerMESH™ layout. In addition to pushing on-resistance significantly down, special care is taken to ensure a very good dv/dt capability for the most demanding applications. Such series complements ST full range of high voltage MOSFETs including revolutionary MDmesh™ products.

Application

■ Switching applications

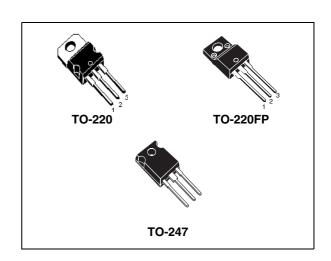


Figure 1. Internal schematic diagram

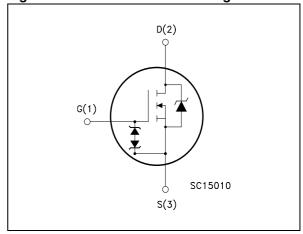


Table 1. Device summary

Order codes	Marking	Package	Packaging
STP8NK80Z	P8NK80Z	TO-220	Tube
STP8NK80ZFP	P8NK80ZFP	TO-220FP	Tube
STW8NK80Z	W8NK80Z	TO-247	Tube

Contents

1	Electrical ratings	3
2	Electrical characteristics	4
	2.1 Electrical characteristics (curves)	6
3	Test circuit	9
4	Package mechanical data	0
5	Revision history1	4

1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Val	Unit	
Symbol	Fai ailletei	TO-220 - TO-247	TO-220FP	
V _{DS}	Drain-source voltage (V _{GS} = 0)	80	0	V
V_{GS}	Gate- source voltage	± 3	30	V
I _D	Drain current (continuous) at T _C = 25°C	6.2	6.2 ⁽¹⁾	Α
I _D	Drain current (continuous) at T _C = 100°C	3.9	3.9 ⁽¹⁾	Α
I _{DM} ⁽²⁾	Drain current (pulsed)	24.8 24.8 ⁽¹⁾		Α
P _{TOT}	Total dissipation at T _C = 25°C	140	30	W
	Derating factor	1.12	0.24	W/°C
V _{ESD(G-S)}	Gate source ESD(HBM-C=100pF, R=1.5KΩ)	400	00	V
dv/dt (3)	Peak diode recovery voltage slope	4.	5	V/ns
V _{ISO}	Insulation withstand voltage (RMS) from all three leads to external heat sink (t=1s; Tc= 25°C)	- 2500		V
T _j T _{stg}	Max operating Junction temperature Storage temperature	-55 to	150	°C

- 1. Limited only by maximum temperature allowed
- 2. Pulse width limited by safe operating area
- 3. $I_{SD} \le 6.2 \text{ A}$, di/dt $\le 200 \text{A/\mu s}$, $V_{DD} \le V_{(BR)DSS}$, $T_j \le T_{JMAX}$.

Table 3. Thermal data

Symbol	Parameter		Unit		
Symbol	raiailletei	TO-220	TO-220FP	TO-247	Oilit
R _{thj-case}	Thermal resistance junction-case max	0.89	4.2	0.89	°C/W
R _{thj-amb}	Thermal resistance junction-ambient max	62.5 50		°C/W	
T _I	Maximum lead temperature for soldering purpose	300			°C

Table 4. Avalanche characteristics

Symbol	Parameter	Value	Unit
I _{AR}	Avalanche current, repetitive or not- repetitive (pulse width limited by Tj Max)	6.2	Α
E _{AS}	Single pulse avalanche energy (starting Tj=25°C, Id=Iar, Vdd=50V)	300	mJ

2 Electrical characteristics

(T_{CASE}=25°C unless otherwise specified)

Table 5. On/off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source Breakdown voltage	$I_D = 1 \text{mA}, V_{GS} = 0$	800			V
I _{DSS}	Zero gate voltage Drain current (V _{GS} = 0)	V _{DS} = Max rating V _{DS} = Max rating, @125°C			1 50	μ Α μ Α
I _{GSS}	Gate-body leakage Current (V _{DS} = 0)	V _{GS} = ± 20 V			± 10	μΑ
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 100 \mu A$	3	3.75	4.5	V
R _{DS(on)}	Static drain-source on resistance	$V_{GS} = 10 \text{ V}, I_D = 3.1 \text{ A}$		1.3	1.5	Ω

Table 6. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
g _{fs} ⁽¹⁾	Forward transconductance	$V_{DS} = 15v, I_D = 3.1 A$		5.2		S
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	$V_{DS} = 25 \text{ V, f} = 1 \text{ MHz,}$ $V_{GS} = 0$		1320 143 27		pF pF pF
C _{oss eq.} (2)	Equivalent output capacitance	$V_{DS} = 0V, V_{DS} = 0V \text{ to } 640V$		58		pF
$\begin{array}{c} t_{\text{d(on)}} \\ t_{r} \\ t_{\text{r(off)}} \\ t_{r} \end{array}$	Turn-on delay time Rise time Turn-off delay time Fall time	$V_{DD} = 400 \text{ V}, I_{D} = 3.1 \text{ A},$ $R_{G} = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see <i>Figure 21</i>)		17 30 48 28		ns ns ns
Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	$V_{DD} = 640 \text{ V}, I_{D} = 6.2 \text{ A},$ $V_{GS} = 10 \text{ V}$		46 8.5 25		nC nC nC
t _{r(Voff)} t _r t _c	Off-voltage rise time Fall time Cross-over time	$V_{DD} = 640 \text{ V}, I_{D} = 6.2 \text{ A},$ $R_{G} = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see <i>Figure 23</i>)		9 9 18		ns ns ns

^{1.} Pulsed: pulse duration=300µs, duty cycle 1.5%

47/

^{2.} $C_{oss\ eq.}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS} .

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD}	Source-drain current Source-drain current (pulsed)				6.2 24.8	A A
V _{SD} ⁽²⁾	Forward on voltage	$I_{SD} = 6.2 \text{ A}, V_{GS} = 0$			1.6	٧
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD} = 6.2 \text{ A, di/dt} = 100 \text{ A/}\mu\text{s}$ $V_{DD} = 50 \text{ V, Tj} = 150^{\circ}\text{C}$ (see <i>Figure 23</i>)		460 2990 13		ns nC A

- 1. Pulsed: pulse duration=300µs, duty cycle 1.5%
- 2. Pulse width limited by safe operating area

Table 8. Gate-source zener diode

	Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Ī	BV _{GSO} ⁽¹⁾	Gate-source breakdown voltage	Igs=± 1mA (Open Drain)	30			V

1. The built-in back-to-back Zener diodes have specifically been designed to enhance not only the device's ESD capability, but also to make them safely absorb possible voltage transients that may occasionally be applied from gate to source. In this respect the Zener voltage is appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated Zener diodes thus avoid the usage of external components.

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area for TO-220

Figure 3. Thermal impedance for TO-220

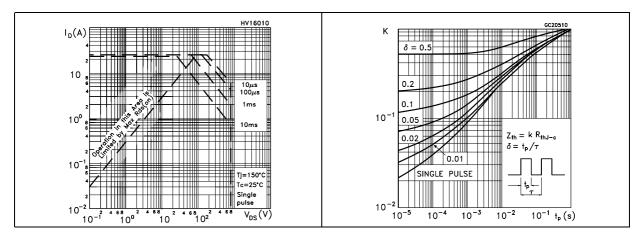


Figure 4. Safe operating area for TO-220FP

Figure 5. Thermal impedance for TO-220FP

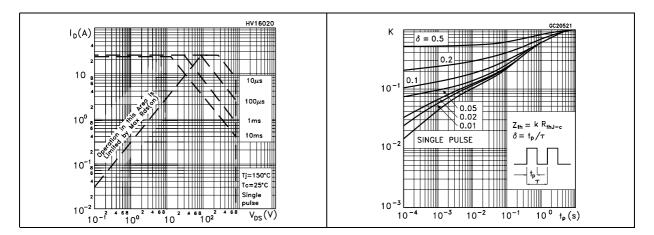
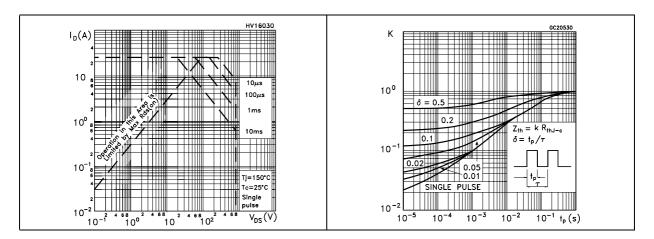


Figure 6. Safe operating area for TO-247

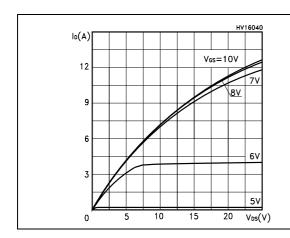
Figure 7. Thermal impedance for TO-247



6/15

Figure 8. Output characteristics

Figure 9. Transfer characteristics



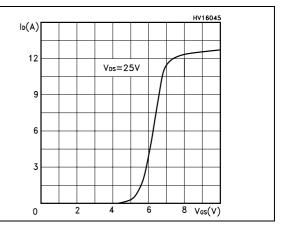
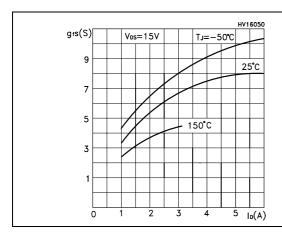


Figure 10. Transconductance

Figure 11. Static drain-source on resistance



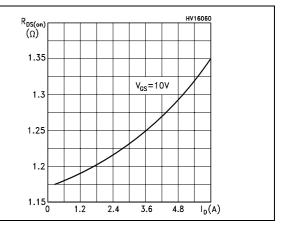
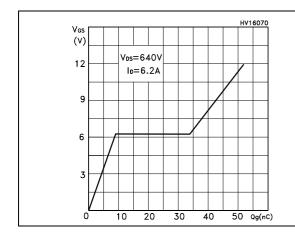


Figure 12. Gate charge vs gate-source voltage Figure 13. Capacitance variations



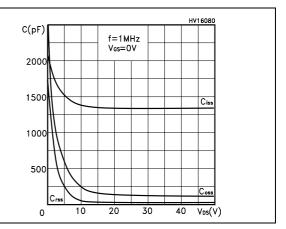


Figure 14. Normalized gate threshold voltage vs temperature

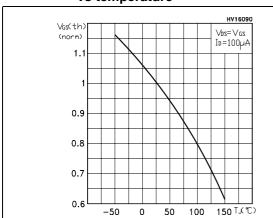


Figure 15. Normalized on resistance vs temperature

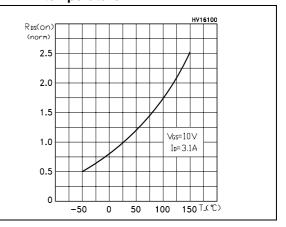
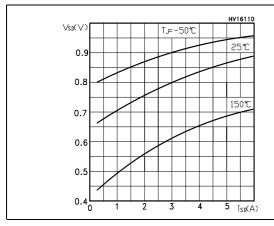


Figure 16. Source-drain diode forward characteristic

Figure 17. Normalized B_{VDSS} vs temperature



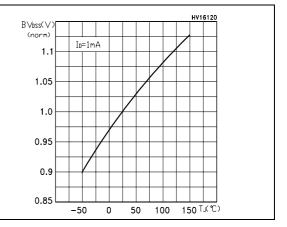
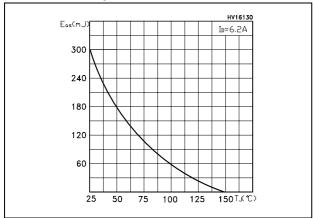


Figure 18. Maximum avalanche energy vs temperature



8/15

3 Test circuit

Figure 19. Unclamped inductive load test circuit

Figure 20. Unclamped inductive waveform

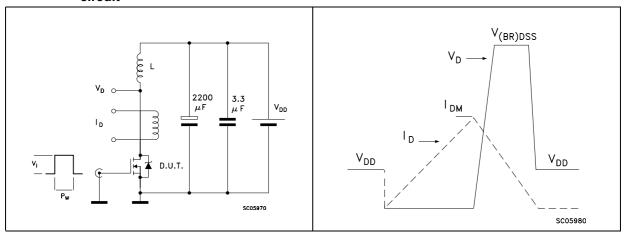


Figure 21. Switching times test circuit for resistive load

Figure 22. Gate charge test circuit

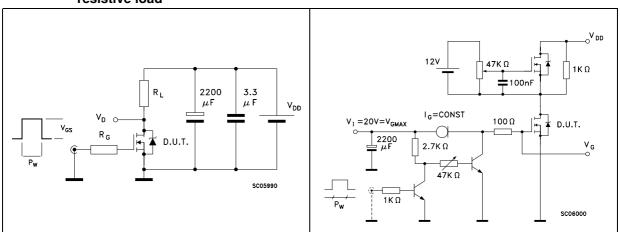
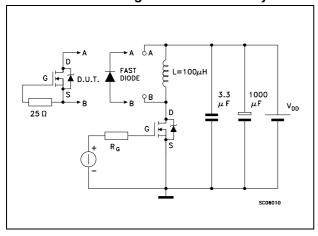


Figure 23. Test circuit for inductive load switching and diode recovery times

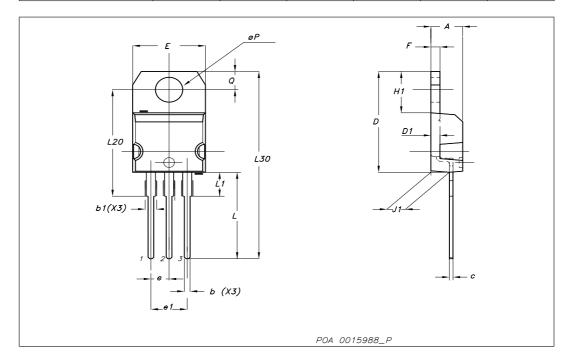


4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect. The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com

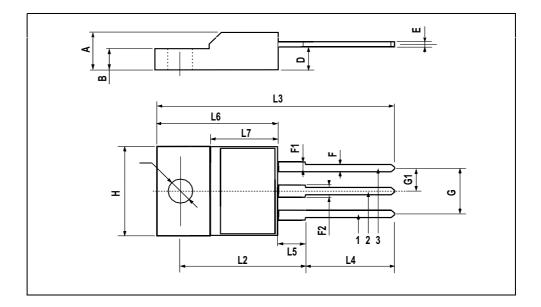
TO-220 mechanical data

Dim		mm			inch	
Dim	Min	Тур	Max	Min	Тур	Max
Α	4.40		4.60	0.173		0.181
b	0.61		0.88	0.024		0.034
b1	1.14		1.70	0.044		0.066
С	0.49		0.70	0.019		0.027
D	15.25		15.75	0.6		0.62
D1		1.27			0.050	
E	10		10.40	0.393		0.409
е	2.40		2.70	0.094		0.106
e1	4.95		5.15	0.194		0.202
F	1.23		1.32	0.048		0.051
H1	6.20		6.60	0.244		0.256
J1	2.40		2.72	0.094		0.107
L	13		14	0.511		0.551
L1	3.50		3.93	0.137		0.154
L20		16.40			0.645	
L30		28.90			1.137	
ØP	3.75		3.85	0.147		0.151
Q	2.65		2.95	0.104		0.116



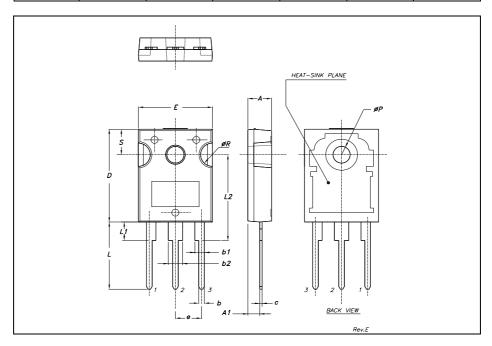
TO-220FP MECHANICAL DATA

DIM		mm.			inch	
DIM.	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
Α	4.4		4.6	0.173		0.181
В	2.5		2.7	0.098		0.106
D	2.5		2.75	0.098		0.108
E	0.45		0.7	0.017		0.027
F	0.75		1	0.030		0.039
F1	1.15		1.7	0.045		0.067
F2	1.15		1.7	0.045		0.067
G	4.95		5.2	0.195		0.204
G1	2.4		2.7	0.094		0.106
Н	10		10.4	0.393		0.409
L2		16			0.630	
L3	28.6		30.6	1.126		1.204
L4	9.8		10.6	.0385		0.417
L5	2.9		3.6	0.114		0.141
L6	15.9		16.4	0.626		0.645
L7	9		9.3	0.354		0.366
Ø	3		3.2	0.118		0.126



TO-247 MECHANICAL DATA

DIM.	mm.			inch		
	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
Α	4.85		5.15	0.19		0.20
A1	2.20		2.60	0.086		0.102
b	1.0		1.40	0.039		0.055
b1	2.0		2.40	0.079		0.094
b2	3.0		3.40	0.118		0.134
С	0.40		0.80	0.015		0.03
D	19.85		20.15	0.781		0.793
Е	15.45		15.75	0.608		0.620
е		5.45			0.214	
L	14.20		14.80	0.560		0.582
L1	3.70		4.30	0.14		0.17
L2		18.50			0.728	
øΡ	3.55		3.65	0.140		0.143
øR	4.50		5.50	0.177		0.216
S		5.50			0.216	



5 Revision history

Table 9. Revision history

Date	Revision	Changes
09-Sep-2004	2	Complete version
17-Aug-2006	3	New template, no content change
20-Apr-2007	4	Typo errors on Table 6
02-Jul-2007	5	Table 2 has been updated

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